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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of: **Kenji MARUYAMA**Group Art Unit: 2813

Serial No.: 09/960,296 Examiner: L. SCHILLINGER

Filed: September 24, 2001 Confirmation No.: 4754

For: SEMICONDUCTOR DEVICE AND METHOD FOR FABRICATING

THE SAME

Attorney Docket Number: 011267

Customer Number: 38834

## <u>PURSUANT TO 37 C.F.R. §1.97(c)(1)</u>

Commissioner for Patents P.O. Box 1450 Alexandria, Virginia 22313-1450

August 23, 2004

Sir:

Applicants direct the attention of the Patent and Trademark Office to the documents listed on the attached Form PTO-1449. A copy of each listed document is attached.

This Information Disclosure Statement is being submitted after issuance of a first official action on the merits and expiration of the three month period following the filing date or the entry of the national stage for the above-captioned application, but prior to issuance of either a final official action or a Notice of Allowance.

The undersigned hereby certifies that each item of information contained in the Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the Information Disclosure Statement.

Information Disclosure Statement under 1.97(c)(1) Attorney Docket No. 011267 Serial No. 09/960,296

The Commissioner is authorized to charge our Deposit Account No. 50-2866 for any fee that is required to effect consideration of this statement.

Respectfully submitted,

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Enclosures: PTO-1449

References

## INFORMATION DISCLOSURE CITATION

Attorney Docket Number. 011267

Serial No. 09/960,296

Applicant(s): Kenji MARUYAMA et al.

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Group Art Unit: 2813

**U.S. PATENT DOCUMENTS** 

Examiner Initial	Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
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Examiner Initial	Document No.	Date	Country	Translation (Yes or No)
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Examiner	Date Considered
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